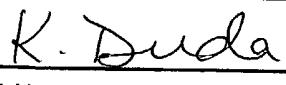


INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) WFS.004C	Application Number 10/673,569 NEW			
				Applicant(s) Daniel R. Neal et al.				
				Filing Date 30 September 2003	Group Art Unit TBA-1756			
				U.S. PATENT DOCUMENTS				
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
KMD  A  B  C  D  E  F  G  H  I  J	A	3,808,035	04-1974	Stelter, Manfred K.	<i>427</i>	<i>74</i>		
		B	4,327,129	04-1982	Sepp, Gunther	<i>427</i>	<i>164</i>	
		C	5,186,975	02-1993	Tizabi et al.	<i>427</i>	<i>99</i>	
		D	5,460,908	10-1996	Reinberg, Alan R.	<i>430</i>	<i>5</i>	
		E	5,534,312	07-1996	Hill et al.	<i>427</i>	<i>533</i>	
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		G	5,691,116	11-1997	Revelli et al.	<i>430</i>	<i>321</i>	
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FOREIGN PATENT DOCUMENTS								
REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation		
						YES	NO	
K	1,298,724	8-13-1987	Canada					
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
L	Snezhko, L.I., "On the accuracy of the Hartmann method for testing aspherical wavefronts," pp. 505-508, Soviet Journal of Optical Technology, Vol. 47, No. 9, September 1980.							
EXAMINER 				DATE CONSIDERED <i>7-20-04</i>				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								